

IN THE CLAIMS

1. (Original) A method, comprising:
processing a request for a voltage overshoot or undershoot to
determine a plurality of inputs based, in part, on a
plurality of waveform parameters;
applying the plurality of inputs to a waveform generation
circuit; and
generating a voltage waveform in accordance with at least one
of the parameters.
2. (Currently Amended) The method of claim 1 wherein the waveform
generation circuit comprises an ~~[[overshoot]]~~ overshoot waveform
generation circuit, and the waveform parameters comprise voltage
overshoot waveform parameters.
3. (Original) The method of claim 1 wherein the waveform
generation circuit comprises an undershoot waveform generation
circuit, and the waveform parameters comprise voltage undershoot
waveform parameters.
4. (Original) The method of claim 1 wherein the waveform
parameters are selected from the group consisting of a magnitude, a
duration, a frequency, and a duty cycle.

5. (Original) The method of claim 1 wherein processing the request comprises determining an oscillation frequency.

6. (Cancelled)

7. (Original) The method of claim 1 wherein processing the request comprises determining a voltage value to apply to a delay circuit.

8. (Original) The method of claim 1 wherein processing the request comprises determining a voltage value to apply to a voltage controlled oscillator.

9. (Original) The method of claim 1 wherein processing the request further comprises processing the request based, in part, on the characteristics of the waveform generation circuit.

10. (Original) The method of claim 1 further comprising generating a circuit reliability model for a device coupled to the waveform generation circuit.

11. (Withdrawn) A circuit for generating voltage overshoots, comprising:

a current regulator adapted to generate voltage overshoot waveforms;

an oscillator coupled to the current regulator, the oscillator controls the operation of the current regulator; and

a programmable delay circuit adapted to control the duration of the overshoot in the voltage overshoot waveforms.

12. (Withdrawn) The circuit of claim 11 wherein the current regulator comprises a charge pump that is activated by a reference clock.

13. (Withdrawn) The circuit of claim 11 wherein the programmable delay circuit comprises a chain of inverting devices.

14. (Withdrawn) A circuit for generating voltage undershoots, comprising:

a current regulator adapted to generate voltage undershoot waveforms;

an oscillator coupled to the current regulator, the oscillator

controls the operation of the current regulator; and

a programmable delay circuit adapted to control the duration of the overshoot in the voltage undershoot waveforms.

15. (Withdrawn) The circuit of claim 14 wherein the current regulator comprises a charge pump that is activated by a reference clock.

16. (Withdrawn) The circuit of claim 14 wherein the programmable delay circuit comprises a chain of inverting devices.

17. (Withdrawn) A method, comprising:
measuring a first frequency and magnitude of quiescent current
through a supply line of a device under test;
injecting voltage overshoots or undershoots into a device under
test; and
measuring, while injecting the voltage overshoots or
undershoots, a second frequency and quiescent current
through the supply line of the device under test.
18. (Withdrawn) The method of claim 17 wherein the first frequency
comprises a pre-stress measurement.
19. (Withdrawn) The method of claim 17 wherein the first frequency
comprises a post-stress measurement.
20. (Withdrawn) The method of claim 17 wherein the voltage
overshoots or undershoots comprise voltage overshoots or undershoots
of a predetermined magnitude.
21. (Withdrawn) The method of claim 17 wherein the voltage
overshoots or undershoots comprises voltage overshoots or
undershoots of a predetermined duration.